

Docket No.: GR 99 P 1058

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Wilfried Dähn
Filed : Concurrently herewith
Title : Integrated Semiconductor Circuit and Method for Functional Testing of Pad Cells

jc688 U.S. PTO

09/484781



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INFORMATION DISCLOSURE STATEMENT

Hon. Commissioner of Patents and Trademarks,
Washington, D.C. 20231

Sir:

In accordance with 37 C.F.R. 1.98 copies of the following patents and/or publications are submitted herewith:

U.S. Patent No. 4,703,484 (Rolfe et al.), dated October 27, 1987;

German Published, Non-Prosecuted Application No. DE 195 45 904 A1 (Eichfeld et al.), dated June 12, 1997, integrated circuit with programmable pad-driver;

Published, European Patent Application No. EP 0 745 859 A2 (Brannigan et al.), dated December 4, 1996.

If no translation of pertinent portions of any foreign language patents or publications mentioned above is included with the aforementioned copies of those applications, patents and/or publications, it is because no existing translation is readily available to the applicant.

Respectfully submitted,

For Applicants

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Date: January 18, 2000

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